

Search Notes

Application/Control No.

10/665,312

Examiner

Quoc A. Tran

Applicant(s)/Patent under
Reexamination

STUPLE ET AL.

Art Unit

2176

SEARCHED

Class	Subclass	Date	Examiner
715	530	6/4/2006	
715	532	6/4/2006	
715	516	6/4/2006	
715	517	6/4/2006	
345	581	7/20/2006	

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
INVENTORS SEARCH CHECK FOR DOUBLE PATENT	6/4/2006	
EAST (US-PAT, US-PGPUB, See Search Histoty Printout	6/4/2006	
ACM Digital Librarysee Search History Printout	6/4/2006	
EAST (US-PAT, US-PGPUB, EPO JPO DERWENT USOCR IBM_TDB) See Search Histoty Printout	7/20/2006	
Internet & Wayback Machine See Search printout	7/20/2006	